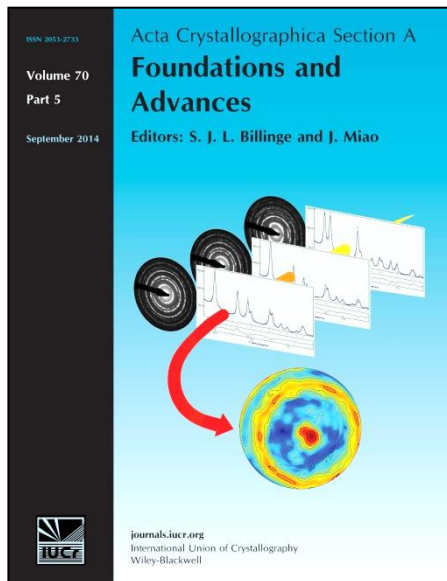


# Structure and Phase Analyses of Nanoparticles using Combined Analysis of TEM scattering patterns

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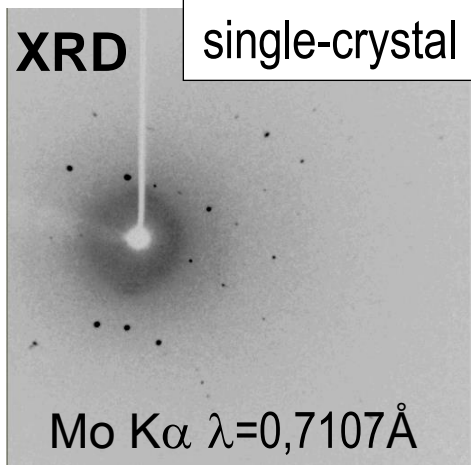
<sup>2</sup> Department of Industrial Engineering, University of Trento, 38123 TRENTO, Italy



1. Phase search and indexing

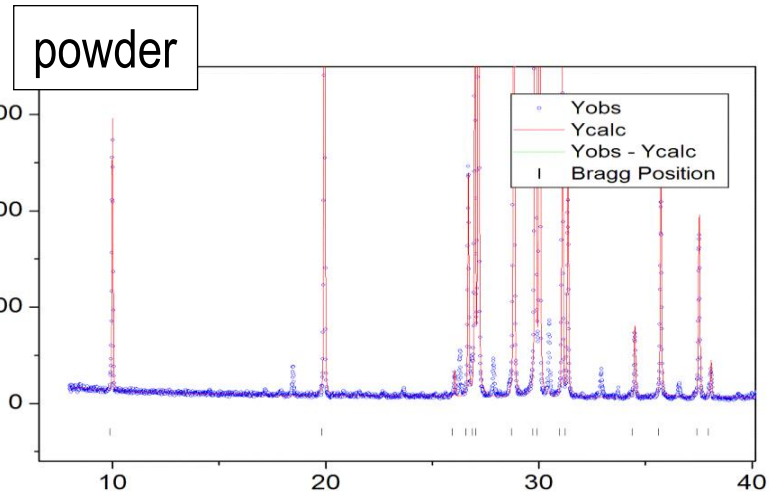
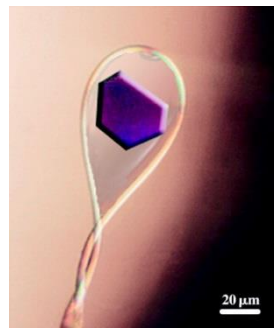
2. Sizes, shapes and textures

3. Structure refinements

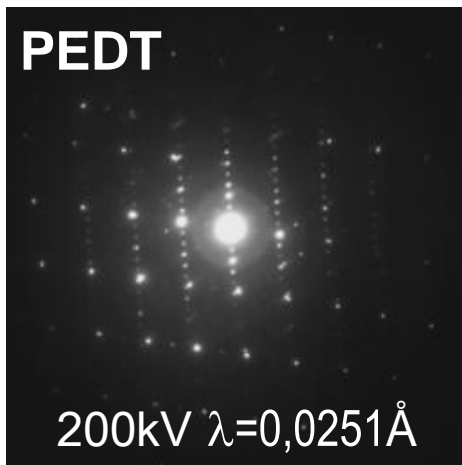


◀ tens of micrometer ▶

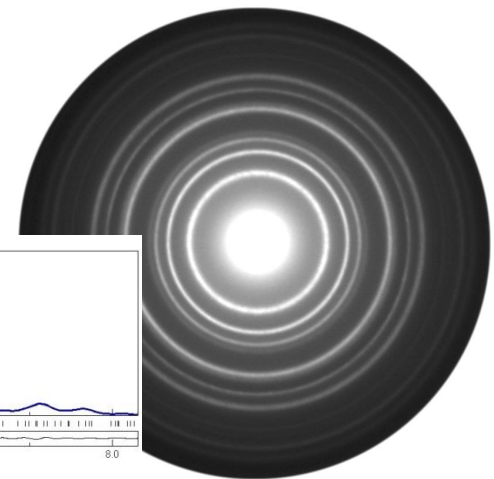
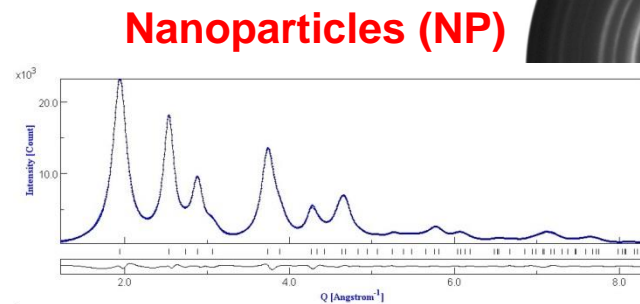
cell, symmetry and structure



phase S/M, structure and microstructure  
(size, shape, texture)



◀ tens of nanometer ▶



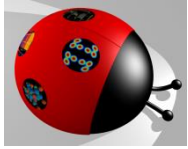
Precession Electron Diffraction Tomography

Electron Powder Diffraction (EDP) patterns

Quantitative and statistically representative analysis of crystallite sizes and shapes, structure and crystallographic texture of nanoparticles in the form of powders and thin films?

Extraction of intensities from electron diffraction “ring patterns” for quantitative or semi-quantitative analysis ...

- Vainshtein (1964), ...
- PCED 2.0 : X.Z. Li, *Ultramicroscopy* 110 (2010) 297-304
- ProcessDiffraction : J.L. Labar, *Microsc. Microanal.* 15 (2009) 20-29
- TextPat : P. Oleynikov, S. Hovmoller and X.D. Zou in *Electron Crystallography*
- **The MAUD program** : L. Lutterotti *Nuclear Inst. and Methods in Physics Res.* B268 (2010) 334-340.



## MAUD Rietveld pattern fitting

Evolutionary  
Simulated Annealing  
Marquardt (Least squares)  
Metadynamics optimization  
Simplex (Nelder-Mead)  
Genetic

Delft size-strain (PV)  
Popa anisotropic  
Size/Strain distributions  
Planar faulting (Warren)  
Turbostratic (Ufer)

## Size-Strain

**Indexing**  
(COD phase search procedure)

**Peak location**

**Peak fitting**

**Structure refinement**

X-ray  
Neutron  
**Electron**

## Texture

March-Dollase  
Harmonic  
(E)WIMV  
Standard Functions

## Residual stresses

Geometric  
Voigt, Reuss, Hill  
Triaxial Stress

Intensity extraction along the rings by segments using an ImageJ plugin

The screenshot shows the MAUD software interface. On the left, a 2D plot displays 'Spectrum # (experimental)' on the y-axis (0 to 100) and '2-Theta (degrees)' on the x-axis (0.30 to 0.90). The plot shows a color-coded intensity distribution. On the right, a diffraction pattern is shown with a red circle around the center. A yellow arrow points to the center with the text '120 patterns' and 'estimation of the center position using a reference circle on the screen'. A red arrow points to the edge of the pattern with the text '3°'. The word 'CAKING' is written in large yellow letters. A blue box at the bottom contains the text 'calibrate the distance specimen/detector ▶ mm to 2θ'. The software interface includes a menu bar, a toolbar, and a 'Plugins' menu that is open, showing options like 'Multi-Spectra from normal transmission/reflection image'.

2D plot

pixel size ▶ pixels to mm

120 patterns

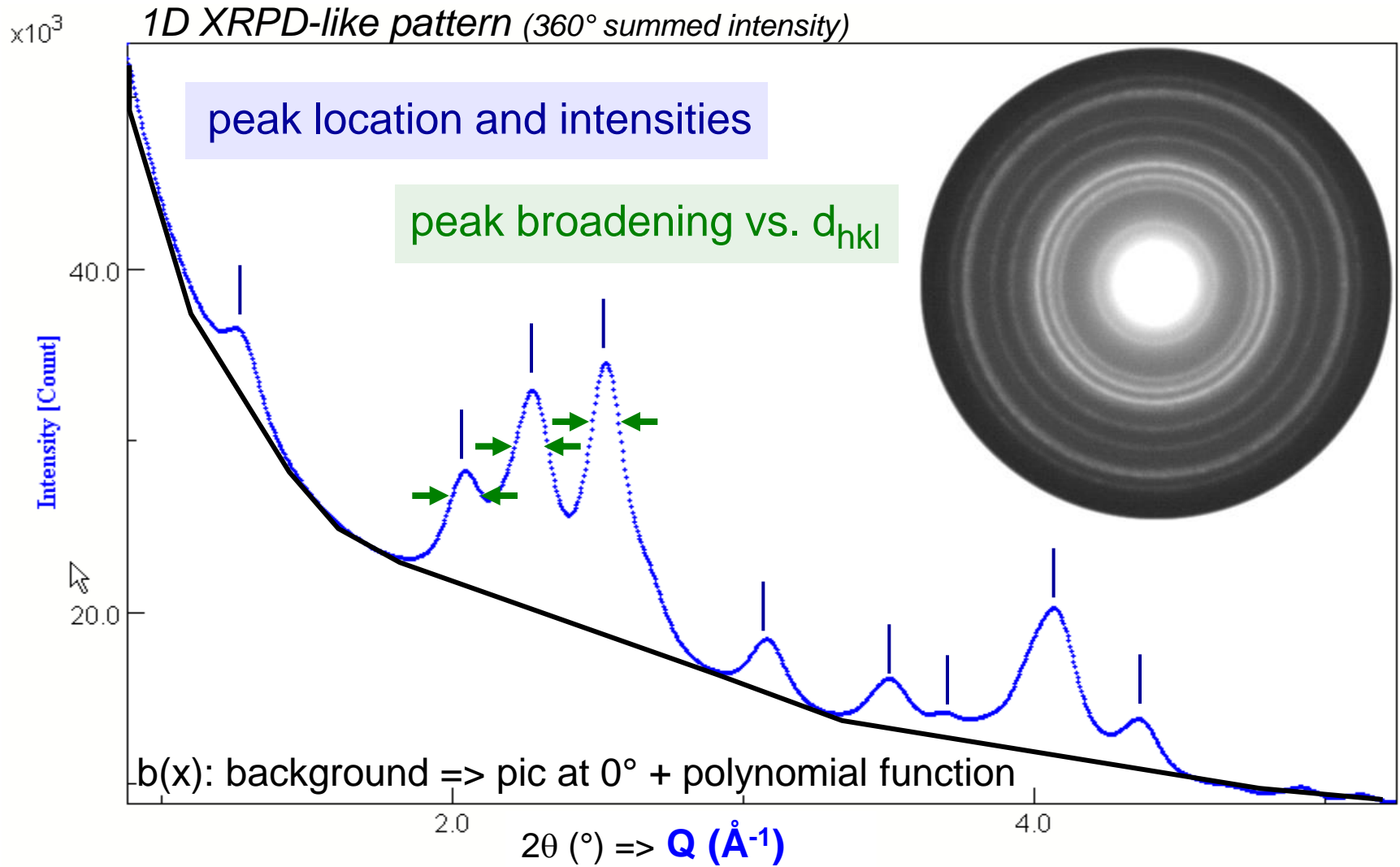
estimation of the center position using a reference circle on the screen

3°

CAKING

chi=phi=0° / omega=90° / eta: 0° to 360°

calibrate the distance specimen/detector ▶ mm to 2θ



$$\text{measured profile } h(x) = f(x) \otimes g(x) + b(x)$$

## Line broadening causes

$$h(x) = f(x) \otimes g(x) + b(x)$$

sample contribution

instrumental broadening

- instrumental broadening
- finite size of the crystals (acts like a Fourier truncation: size broadening)
- imperfection of the periodicity (due to  $d_h$  variations inside crystals: microstrain effect)
- generally: 0D, 1D, 2D, 3D defects

All quantities are average values over the probed volume

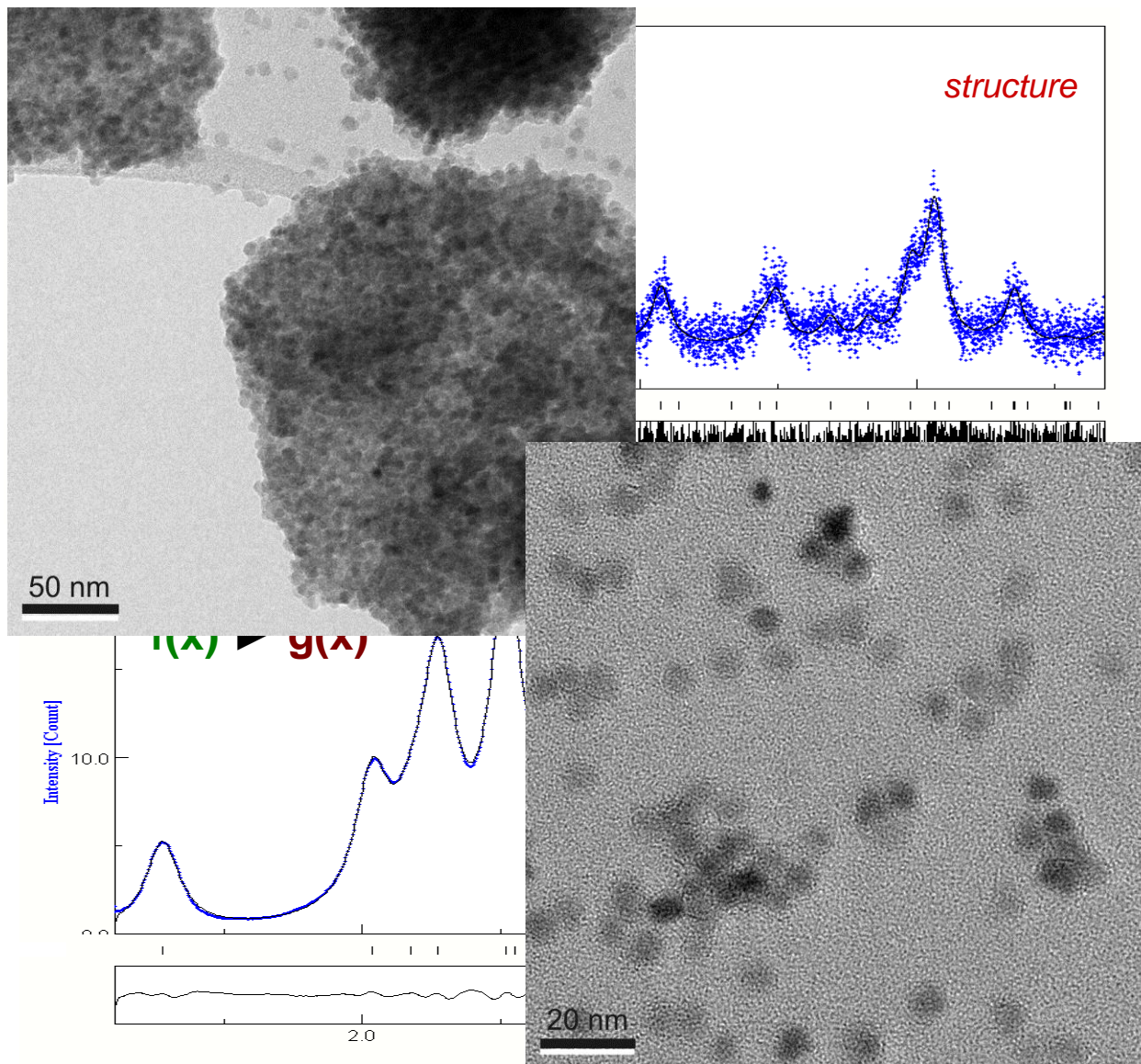
- ▶ electrons, x-rays, neutrons: complementary
- ▶ distributions: mean values depend on distributions' shapes

Extraction of  $f(x)$  can be obtained by a whole-pattern (Rietveld) analysis

Need to know  $g(x)$  the instrumental broadening !

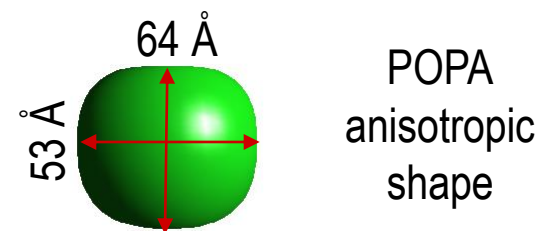
**The instrumental Peak Shape Function is obtained by analysing nanoparticles of known sizes and shapes as obtained from X-ray analyses**

Mn<sub>3</sub>O<sub>4</sub> hausmannite (*L. Sicard et al, J. Magn. Magn. Mater. 322 (2010) 2634-2640*)



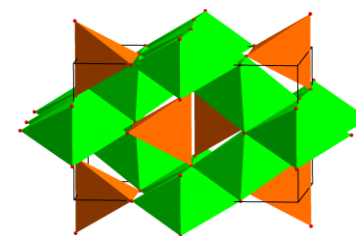
Bruker D8 / Lynx Eye 1D  
 $\lambda=1.54056 \text{ \AA}$  (Cu K $\alpha_1$ )

SG: I 4<sub>1</sub>/a m d  
 $a=5.764(2)\text{\AA}$  and  $c=9.448(4)\text{\AA}$



TOPCON 2B / CCD ORIUS  
 $\lambda=0.0251\text{\AA}$

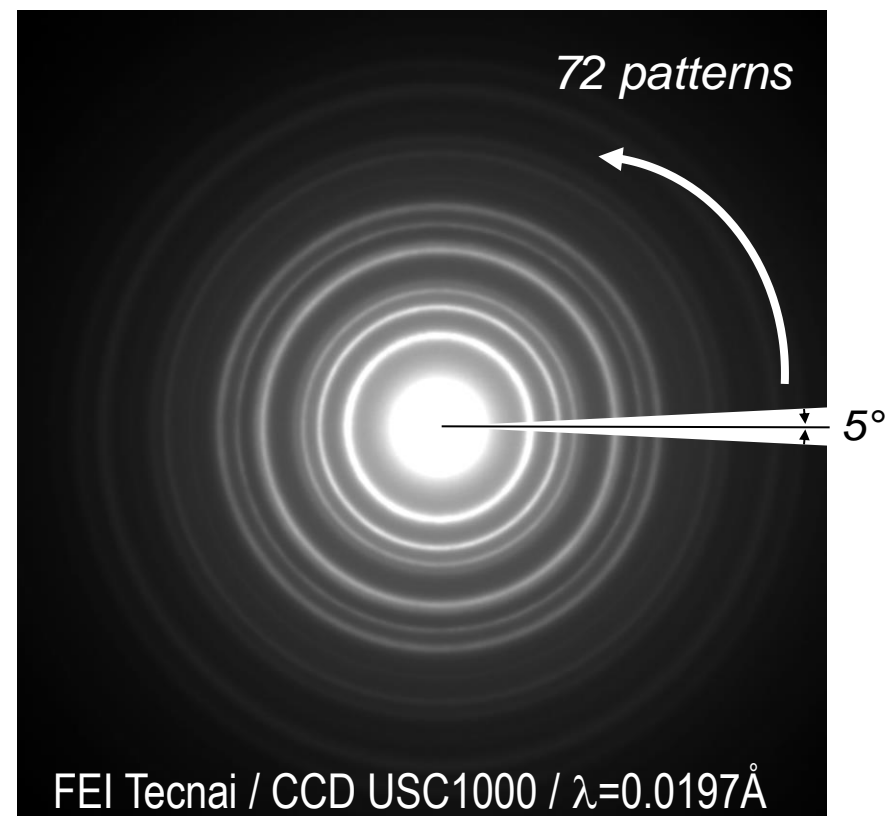
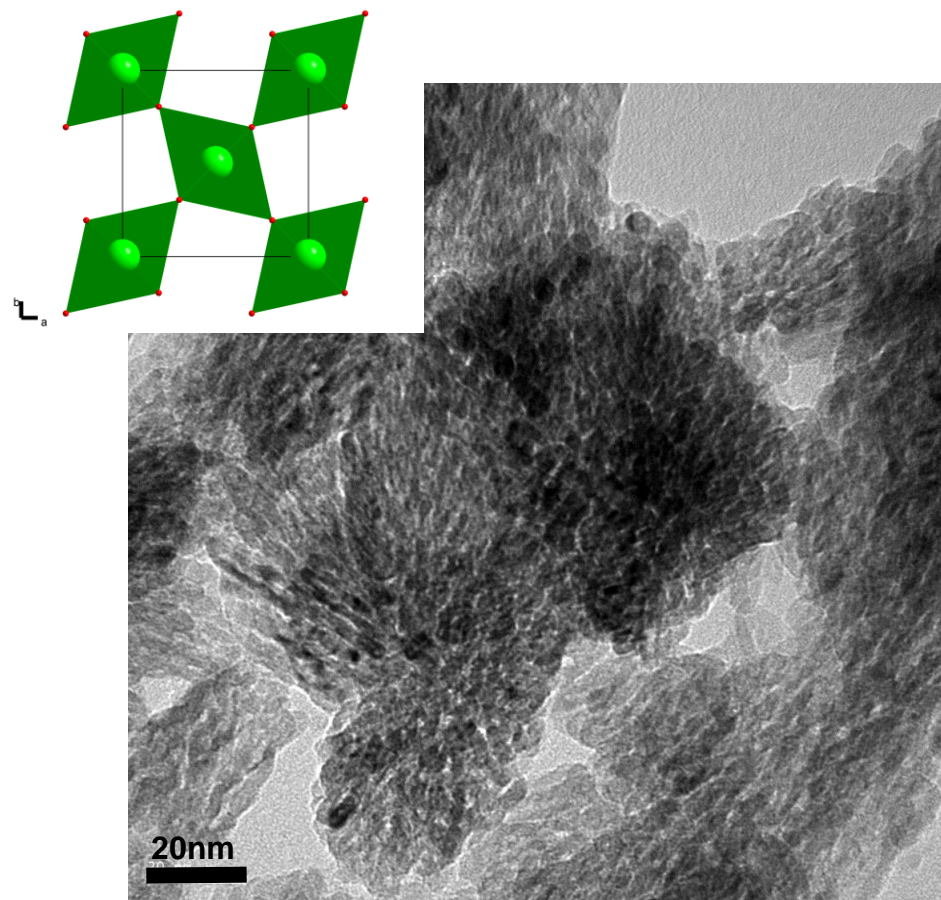
$a=5.7757(2)\text{\AA}$  and  $c=9.4425(4)\text{\AA}$



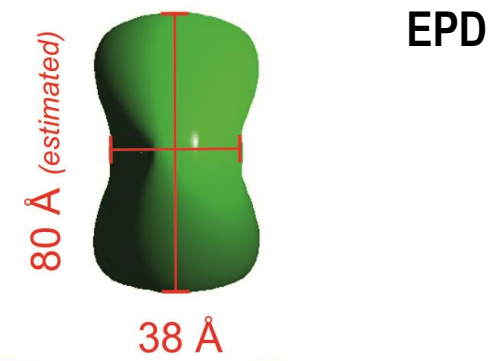
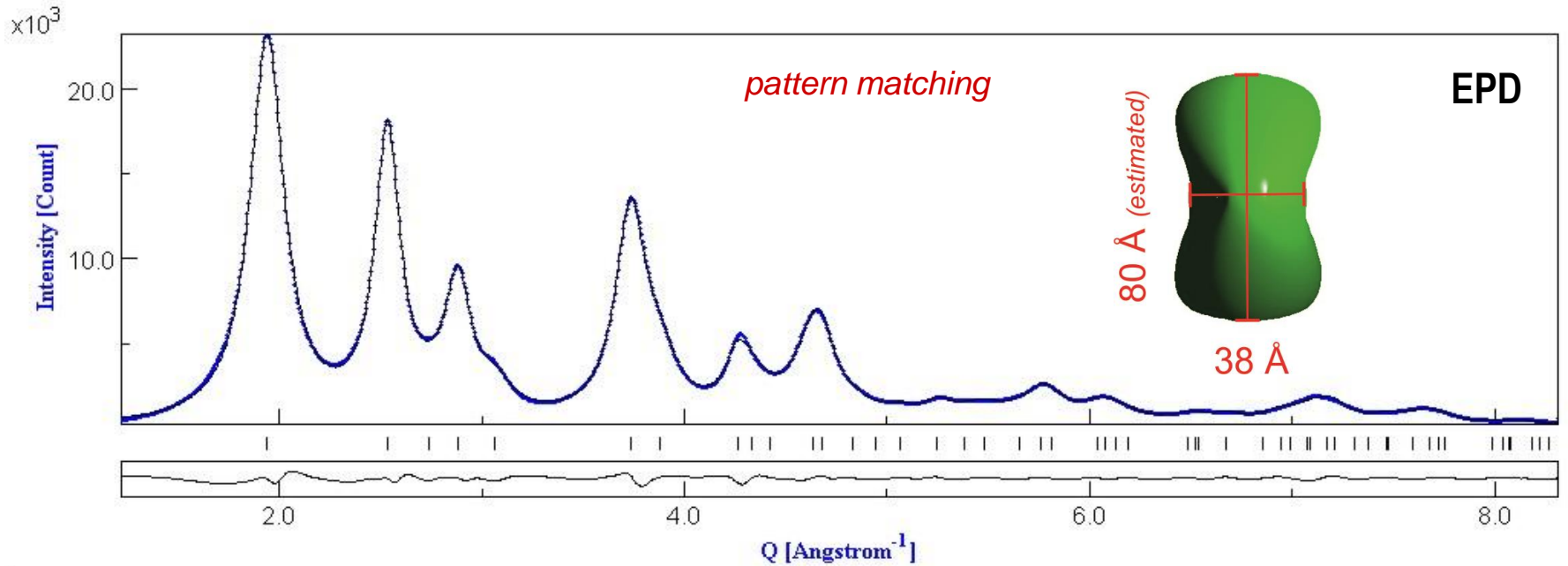
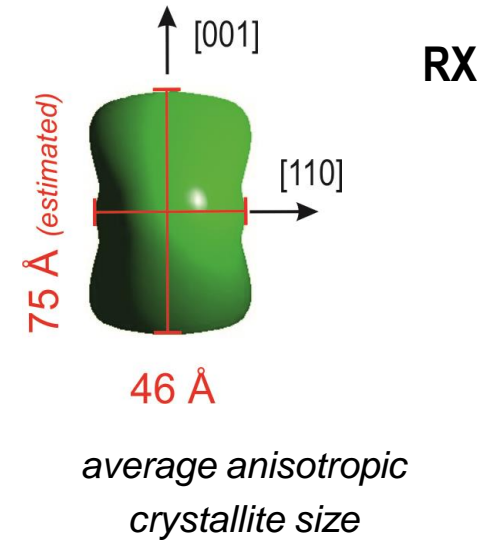
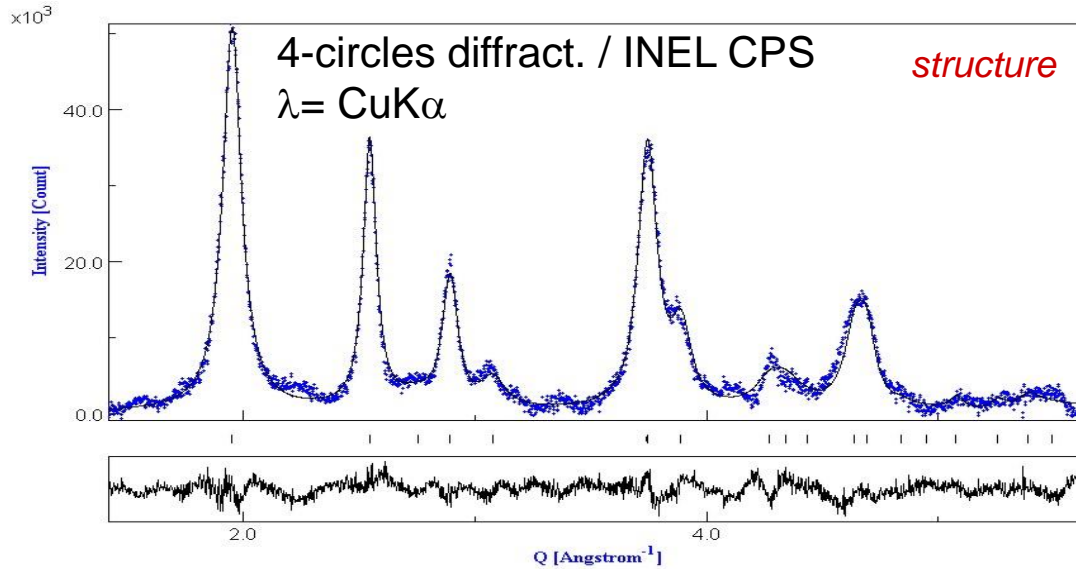


Microstructure of nanocrystalline materials: TiO<sub>2</sub> rutile <sup>(1)</sup>

from phase search: TiO<sub>2</sub> rutile  $P4_2/mnm$   $a=4.592\text{\AA}$   $a=2.957\text{\AA}$  (COD database ID n°9001681)



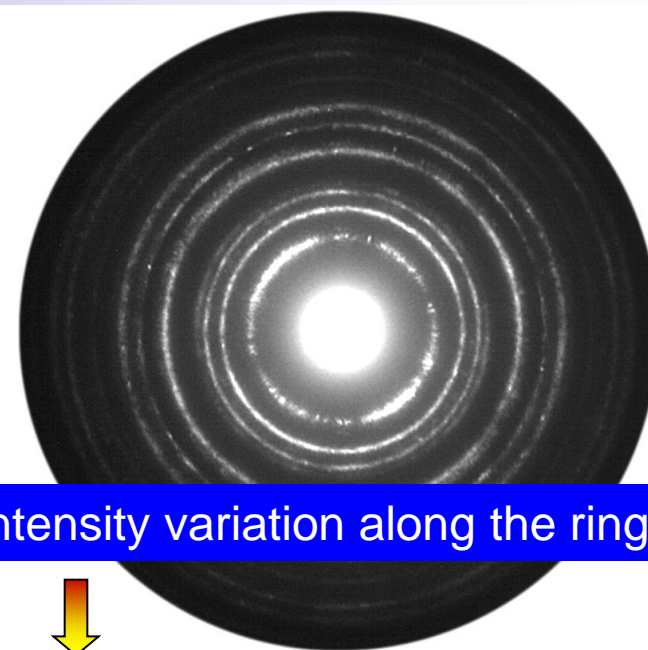
(1) M. Reddy et al., *ElectroChem. Com.* 8 (2006) 1299-1303



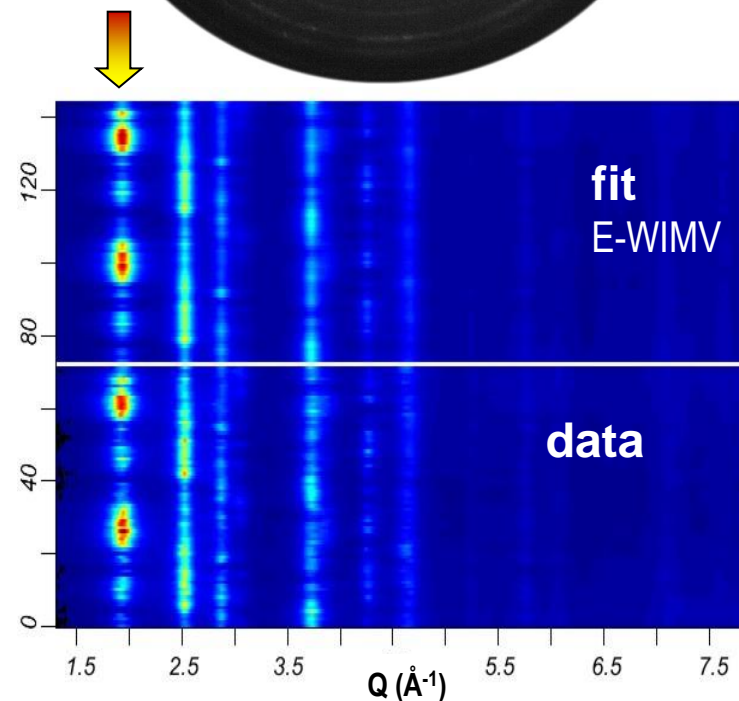
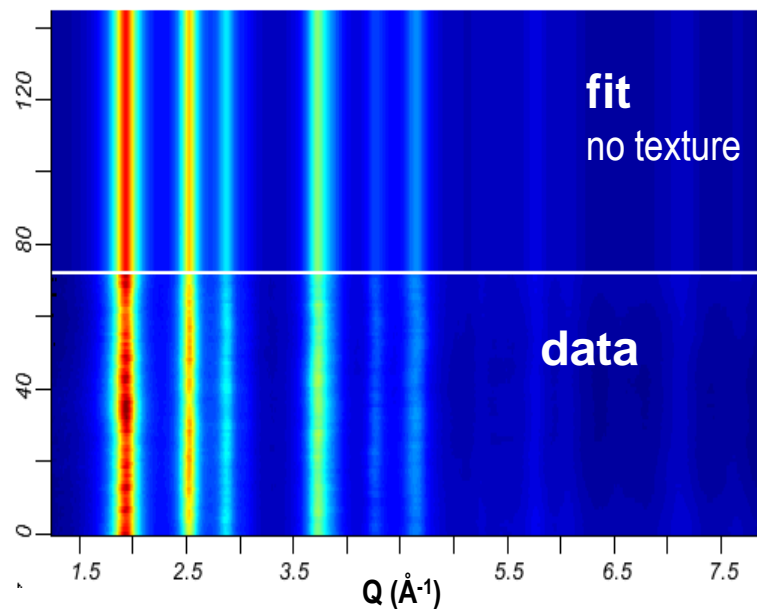


6  $\mu\text{m}$   $\longrightarrow$  0.5  $\mu\text{m}$

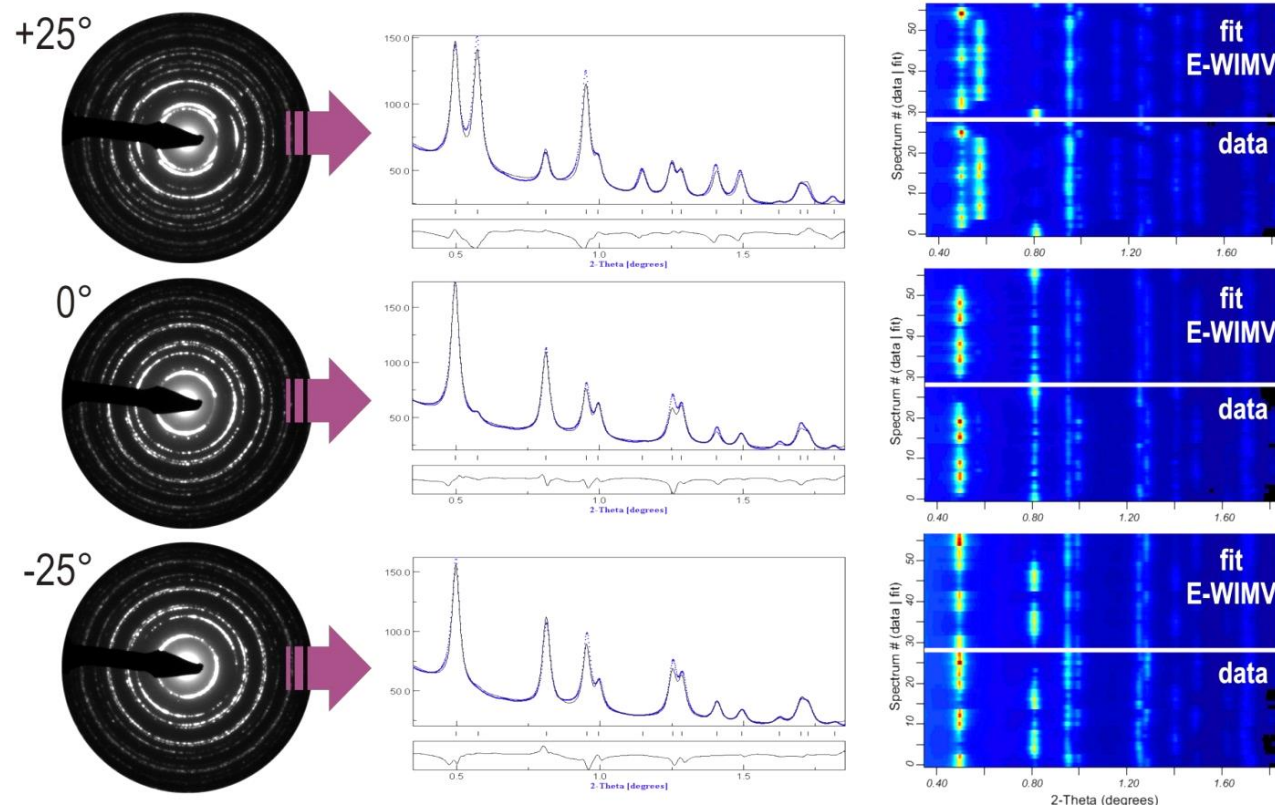
decreasing the  
selected area



Texture :: intensity variation along the rings

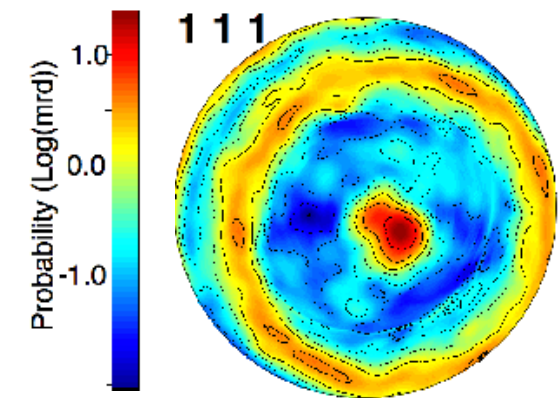


The features available in MAUD allow a full quantitative texture analysis for general cases (not only fiber textures) from EPD patterns with the obtention of accurate pole figures



+25° to -25° step 5°

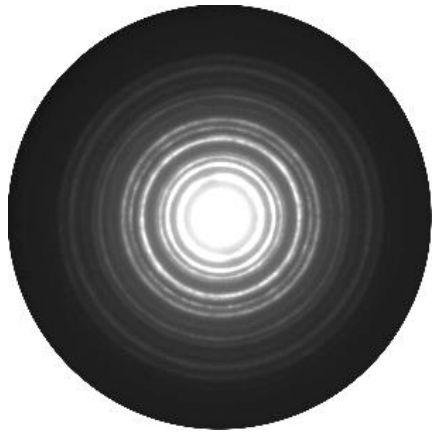
QTA analysis of  
Pt thin film  
deposited on Si



{111} pole figure from ODF refinement

For application on textured thin film see also M. Gemmi et al., *J. Appl. Cryst.* 44 (2011)

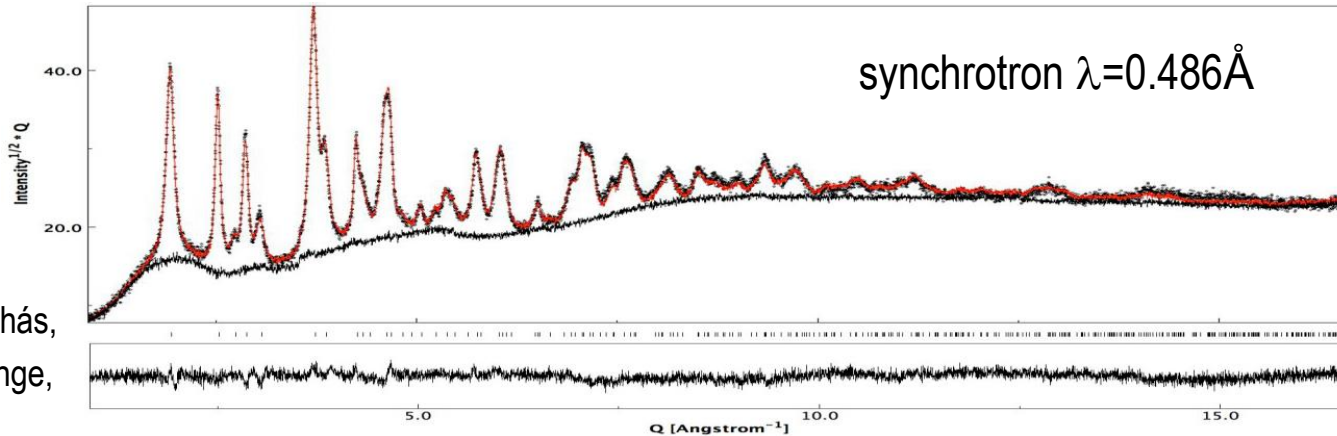
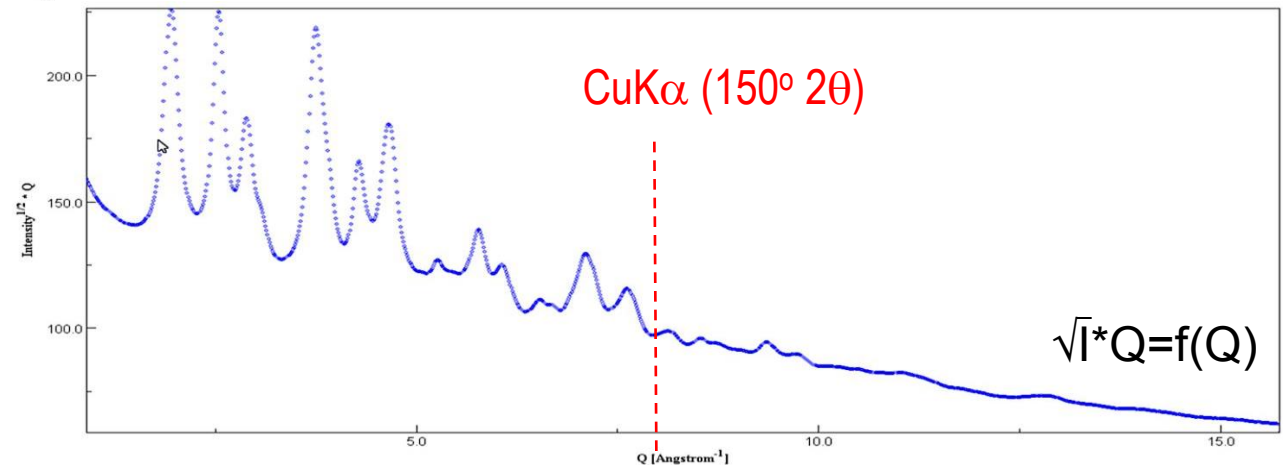
- ▶ microstructural features can be obtained in the pattern-matching mode
- ▶ not convincing using structure factors from kinematical approximation ...
- ... much better when using the 2-beam or Blackman correction

NP TiO<sub>2</sub> rutile

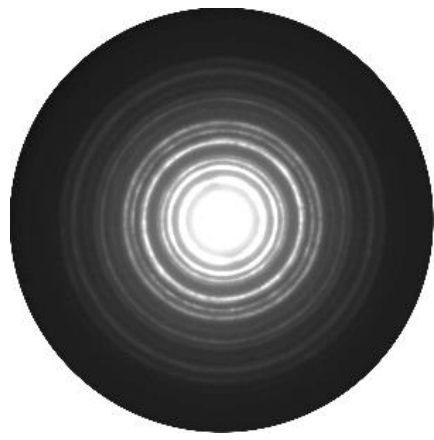
Pair Distribution Function  
analyses on EPD



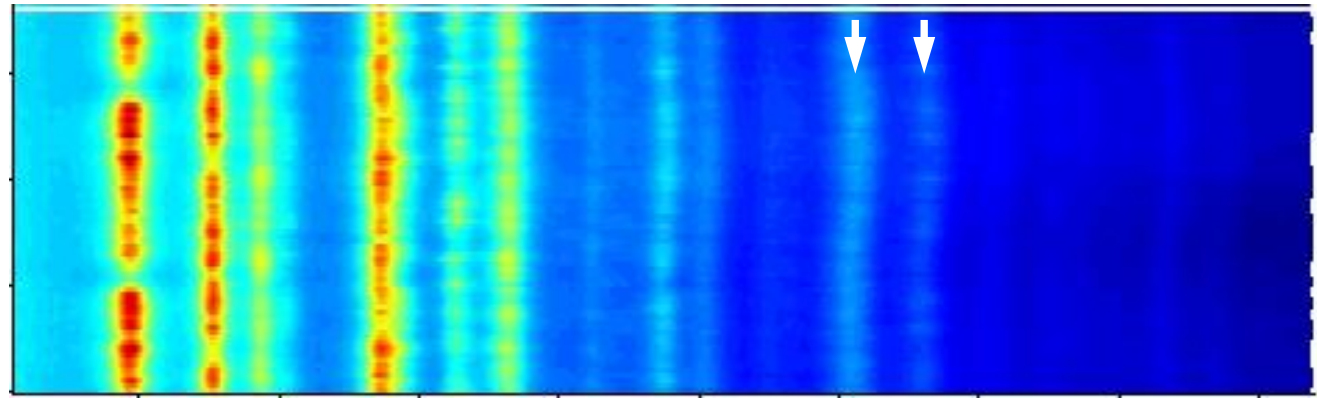
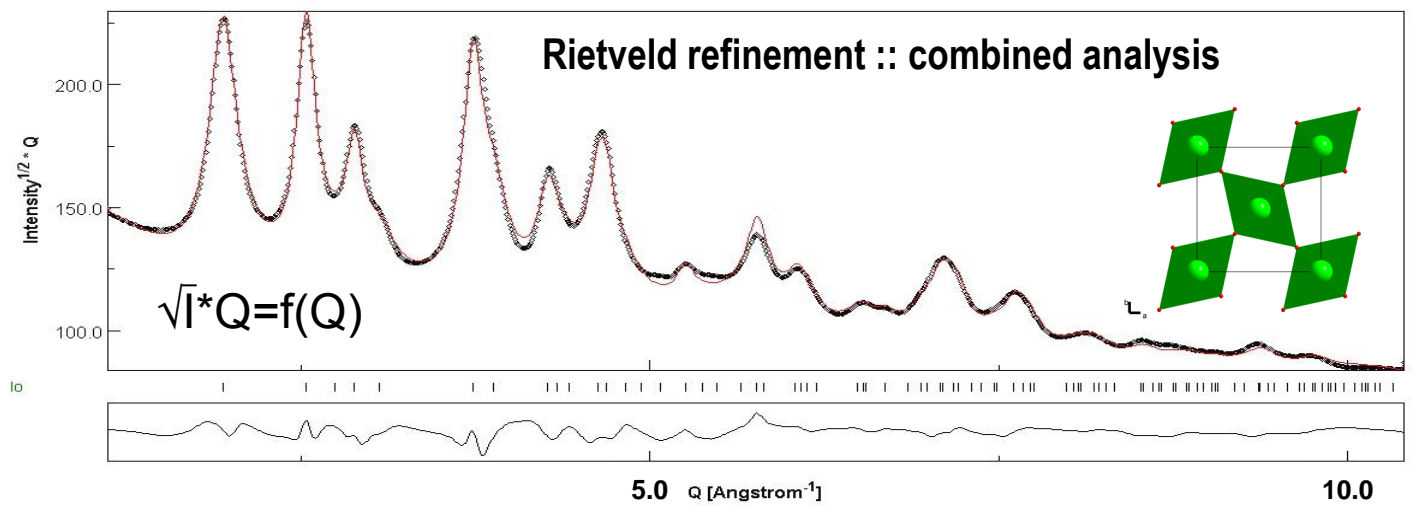
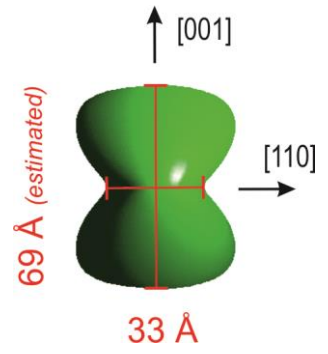
A.M.M. Abeykoon, C.D. Malliakas, P. Juhás,  
E.S. Božin, M.G. Kanatzidis, S.J.L. Billinge,  
Z. Kristallogr. 227 (2012) 248



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- ▶ not convincing using structure factors from kinematical approximation ...
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NP TiO<sub>2</sub> rutile



# Structure and Phase Analyses of Nanoparticles using Combined Analysis of TEM scattering patterns

- automatic phase search procedure (COD database, multi-phases)

**Diffraction pattern and sample composition**

Upload diffraction pattern:  no file selected

Structures database:

Atomic elements in the sample:

Threshold phase density:  Maximum number of phases:

Crystallisation:

**Experiment details**

Radiation:

X-ray tube:

Other:  Wavelength (Å):

Instrument geometry:

Bragg-Brentano (theta-2theta)

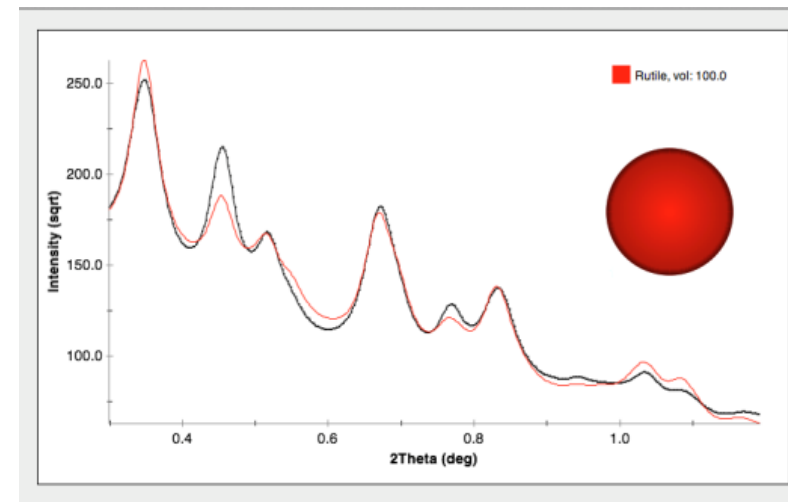
Bragg-Brentano (2theta only), omega:

Debye-Scherrer

Transmission

Instrument broadening function:

whole-pattern S/M procedure  
(kinematical approximation)



<http://nanoair.dii.unitn.it:8080/sfpm> and <http://cod.iutcaen.unicaen.fr>

## Structure and Phase Analyses of Nanoparticles using Combined Analysis of TEM scattering patterns

- automatic phase search procedure (COD database, multi-phases)
- average lattice cell parameters and crystallite size (anisotropic shapes)
- accurate texture analysis (general cases, ODF, ...)
  - ... can be obtained in the Pattern matching mode
- structure refinements are possible within MAUD (kinematic or Blackman)
  - ... implementation of PDF approach soon

**Thank you for your attention**

V. Pralong and V. Caignaert (TiO<sub>2</sub> nanoparticules) @ CRISMAT – Caen

L. Sicard and S. Ammar (Mn<sub>3</sub>O<sub>4</sub> nanoparticules) @ ITODYS – Paris 7

S. Gascoin (XRD measurements) @ CRISMAT – Caen

ANR FURNACE, BAMBI